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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Application Number

Filing Date

Concurrently herewith

First Named Inventor

Payman

Group Art Unit

2858

Examiner Name

A. Deb

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of

1

Attorney Docket Number

040857/291463

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear
/AD/	1	US-4,779,041	10-18-1988	Williamson, Jr.	
↓	2	US-5,280,237	01-18-1994	Buks	
	3	US-5,365,180	11-15-1994	Edelman	
	4	US-5,554,928	09-10-1996	Stringer	
	5	US-5,521,513	05-28-1996	Stringer	
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	8	US-6,188,235	02-13-2001	Buks et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code - Number Kind Code. (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached
/AD/	9	EP 0 571 963 A2	12-01-1993	SPEA S.r.l. Sistemi et al.		
↓	10	EP 0 622 733 A1	11-02-1994	SGS-Thomson Microelectronics s.r.l.		

OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
/AD/	11	Analog AC Harmonic Method for Detecting Solder Opens, C. Robinson, IEEE Proceedings of the International Test conference, 1997	
↓	12	Nonlinear Distortion Voltage Testing of Contact Surfaces, I. Minowa et al., Conference Proceedings Article, September 26, 1988, pp. 277-280	
Examiner Signature	/Anjan Deb/ (07/03/2007)		Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. #4708773v1